Power MOSFET30 V, 63 A, Single N-Channel, DPAK/IPAK

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- NVD Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These are Pb-Free Devices

Applications

- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Para	Symbol	Value	Unit		
Drain-to-Source Vo	Drain-to-Source Voltage				V
Gate-to-Source Vol	Gate-to-Source Voltage			±20	V
Continuous Drain		T _A = 25°C	Ι _D	13.8	Α
Current R _{θJA} (Note 1)		T _A = 85°C		10.7	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	2.63	W
Continuous Drain	1	T _A = 25°C	ID	10	Α
Current R _{θJA} (Note 2)	Steady State	T _A = 85°C		7.8	
Power Dissipation R _{θJA} (Note 2)	State	T _A = 25°C	P _D	1.4	W
Continuous Drain		T _C = 25°C	I _D	63	Α
Current R _{θJC} (Note 1)		T _C = 85°C		49	
Power Dissipation $R_{\theta JC}$ (Note 1)		T _C = 25°C	P _D	54.6	W
Pulsed Drain Current	t _p =10μs	T _A = 25°C	I _{DM}	126	Α
Current Limited by P	ackage	T _A = 25°C	I _{DmaxPkg}	45	Α
Operating Junction and Storage Temperature			T _J , T _{STG}	-55 to +175	°C
Source Current (Boo	Source Current (Body Diode)			45	Α
Drain to Source dV/dt			dV/dt	6	V/ns
Single Pulse Drain-to-Source Avalanche Energy (V_{DD} = 24 V, V_{GS} = 10 V, I_L = 17 A_{pk} , L = 1.0 mH, R_G = 25 Ω)			EAS	144.5	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

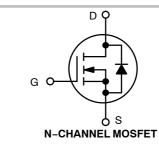
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX		
30 V	8.0 mΩ @ 10 V			
	12.4 mΩ @ 4.5 V	63 A		



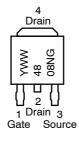


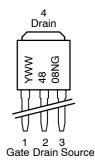
DPAK CASE 369AA STYLE 2



IPAK CASE 369D STYLE 2

MARKING DIAGRAMS & PIN ASSIGNMENTS





Y = Year

WW = Work Week

4808N = Device Code

G = Pb-Free Package

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 6 of this data sheet.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{\theta JC}$	2.75	
Junction-to-TAB (Drain)	$R_{\theta JC-TAB}$	3.5	°C/W
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	57	C/VV
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	107	

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condi	tion	Min	Тур	Max	Unit
OFF CHARACTERISTICS	<u> </u>						
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				27		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 \text{ V},$ $T_{J} = 25 ^{\circ}\text{C}$				1	μΑ
	V _{DS} = 24 V		T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 250 μΑ	1.5		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.6		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 to 11.5 V	I _D = 30 A		6.7	8.0	
			I _D = 15 A		6.6		mΩ
		V _{GS} = 4.5 V	I _D = 30 A		10.3	12.4	
			I _D = 15 A		9.8		
Forward Transconductance	9FS	V _{DS} = 15 V, I _D = 15 A			11.4		S
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}				1538		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 12 V			334		pF
Reverse Transfer Capacitance	C _{RSS}				180		1
Total Gate Charge	Q _{G(TOT)}				11.3	13	
Threshold Gate Charge	Q _{G(TH)}		5 \		1.6		nC
Gate-to-Source Charge	Q _{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 1$	5 V; I _D = 30 A		4.9		
Gate-to-Drain Charge	Q_{GD}				4.9		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 11.5 V, V _{DS} = 15 V; I _D = 30 A			26		nC
SWITCHING CHARACTERISTICS (Note	4)			-		-	•
Turn-On Delay Time	t _{d(ON)}				12.3		
Rise Time	t _r	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			21.3		
Turn-Off Delay Time	t _{d(OFF)}				14.6		ns
						t e	1

- 3. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
- 4. Switching characteristics are independent of operating junction temperatures.

6.0

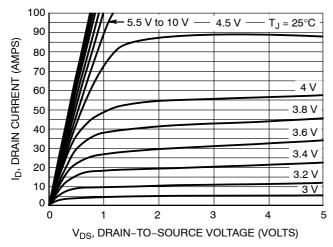
Fall Time

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 4)			•	•		
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 11.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			7.7		
Rise Time	t _r				19.5		
Turn-Off Delay Time	t _{d(OFF)}	I _D = 15 A, R _G :	= 3.0 Ω		23		ns
Fall Time	t _f	1			3.5		
DRAIN-SOURCE DIODE CHARACTE	RISTICS						
Forward Diode Voltage	V _{SD}	$V_{GS} = 0 \text{ V}.$ $T_J = 25^{\circ}\text{C}$			0.93	1.2	
		$V_{GS} = 0 \text{ V},$ $I_S = 30 \text{ A}$ $T_J = 125^{\circ}\text{C}$	T _J = 125°C		0.83		V
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			20		
Charge Time	ta				10.4		ns
Discharge Time	t _b				9.6		
Reverse Recovery Charge	Q _{RR}				9.7		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S	T _A = 25°C			2.49		nΗ
Drain Inductance, DPAK	L _D				0.0164		
Drain Inductance, IPAK	L _D				1.88		
Gate Inductance	L _G				3.46		
Gate Resistance	R _G				1.1		Ω

Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

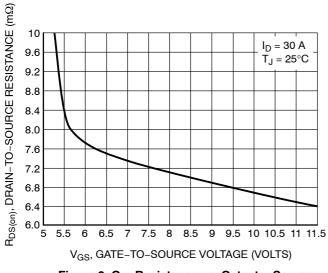
TYPICAL PERFORMANCE CURVES



80 $V_{DS} \ge 10 \text{ V}$ 70 DRAIN CURRENT (AMPS) 60 50 40 30 $T_J = 125^{\circ}C$ 20 T_J = 25°C ے $T_J = -55^{\circ}C$ 0 3 5 V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



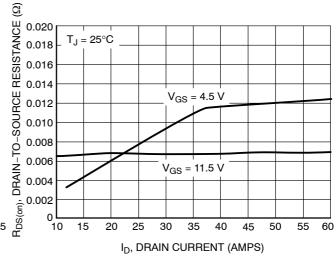
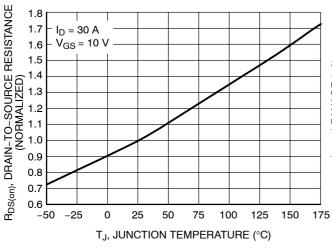


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



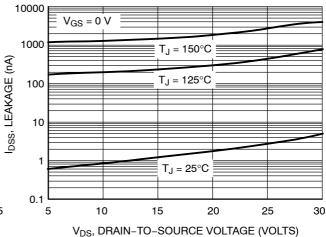
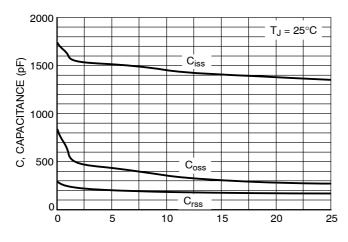


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Drain Voltage

TYPICAL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

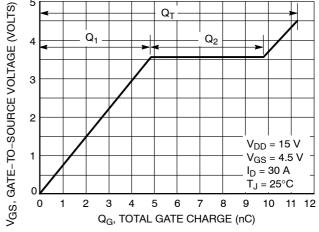


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge



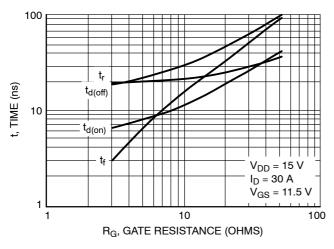


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

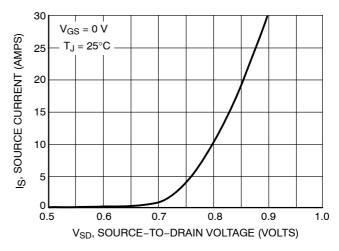


Figure 10. Diode Forward Voltage vs. Current

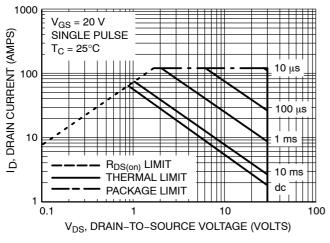


Figure 11. Maximum Rated Forward Biased Safe Operating Area

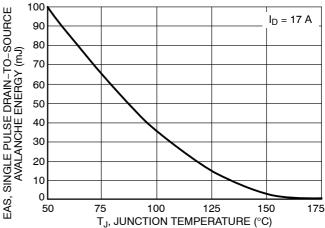


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL PERFORMANCE CURVES

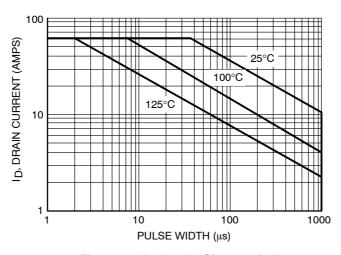


Figure 13. Avalanche Characteristics

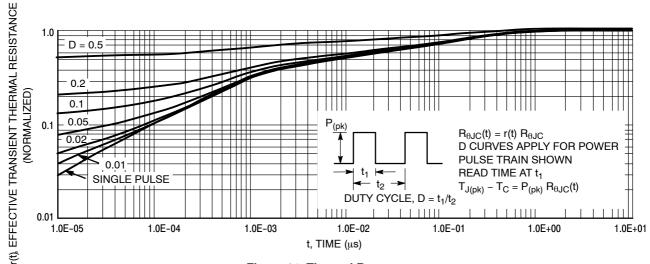


Figure 14. Thermal Response

ORDERING INFORMATION

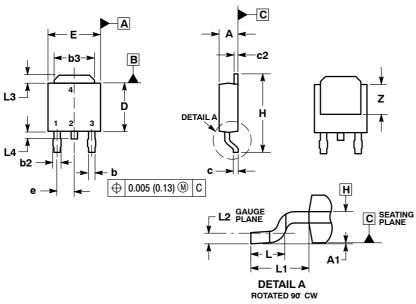
Device	Package	Shipping [†]
NTD4808NT4G	DPAK (Pb-Free)	2500 / Tape & Reel
NTD4808N-1G	IPAK (Pb-Free)	75 Units / Rail
NVD4808NT4G	DPAK (Pb-Free)	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS

DPAK (SINGLE GUAGE)

CASE 369AA-01 **ISSUE B**



NOTES:

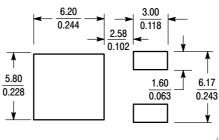
- 1. DIMENSIONING AND TOLERANCING PER ASME

- 1. DIMENSIONING AND TOLEHANCING PEH ASME Y14.5M, 1994.
 2. CONTROLLING DIMENSION: INCHES.
 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS b3, L3 and Z.
 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0,006 INCHES PER SIDE.
- 5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INC	HES	MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A 1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
O	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
Е	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29	BSC	
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L	0.108 REF		2.74	REF	
L2	0.020	BSC	0.51	BSC	
Ľ	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN

SOLDERING FOOTPRINT*

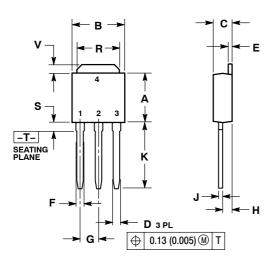


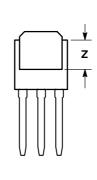
SCALE 3:1

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

IPAK CASE 369D-01 ISSUE C





NOTES:

- 1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIMETER		
DIM	MIN	MAX	MIN	MAX	
Α	0.235	0.245	5.97	6.35	
В	0.250	0.265	6.35	6.73	
С	0.086	0.094	2.19	2.38	
D	0.027	0.035	0.69	0.88	
Е	0.018	0.023	0.46	0.58	
F	0.037	0.045	0.94	1.14	
G	0.090	0.090 BSC 2		BSC	
Н	0.034	0.040	0.87	1.01	
ſ	0.018	0.023	0.46	0.58	
K	0.350	0.380	8.89	9.65	
R	0.180	0.215	4.45	5.45	
S	0.025	0.040	0.63	1.01	
٧	0.035	0.050	0.89	1.27	
Z	0.155		3.93		

STYLE 2: PIN 1. GATE

- 2. DRAIN
- 3. SOURCE
- 4. DRAIN

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